3:40 F-45 SRM 2855 Additive Elements in Polyethylene WDXRF Analyses and Certification Approach
J.R. Sieber, *National Institute of Standards and Technology, Gaithersburg, MD*

4:00 F-43 Oxidic Calibration Using WDXRF-Multiscat®: Applications Shown for Minerals, Ore Concentrates And Slags
S. Bäckman, I. Bernhardsson, *XRF Analytical AB, Sweden*

4:20 F-31 Classes of Materials (COM)—A Tool for Analysis and Material Identification
J. Kessler, V. Roßiger, *Helmut Fischer GmbH+Co.KG, Sindelfingen, Germany*
M. Haller, *Fischer Technology, Windsor, CT*

4:40 F-54 Stardust Cometary Matter Analyzed By Synchrotron Nano-XRF: New Results And Developments
T. Schoonjans, B. Vekemans, G. Silversmit, L. Vincze, *Ghent University, Gent, Belgium*
S. Schmitz, F. Brenker, *Institut für Geowissenschaften, Frankfurt, Germany*

5:00 F-64 L Shell X-ray Fluorescence Cross-Sections for Elements with $33 \leq Z \leq 50$
V. Sharma, N. Singh, S. Kumar, *Panjab University, Chandigarh, India*

XRD: High Resolution XRD
Friday a.m. Pikes Peak 1 & 2

Chair: **B. Tanner,** *University of Durham, Durham, United Kingdom*

8:30 D-15 *Invited*— Laboratory-Based Characterization of Heteroepitaxial Structures: Advanced Experiments Not Needing Synchrotron Radiation
P. Zaumseil, *IHP, Frankfurt, Germany*

9:00 D-67 High-Resolution X-ray Diffraction Data Analysis From The Partly Relaxed Semiconductor Structures
A. Ulyanenkov, *Bruker AXS GmbH, Karlsruhe, Germany*
A. Benediktovitch, I. Feranchuk, *Belarussian State University, Minsk, Belarus*
B. He, H. Ress, *Bruker AXS, Inc., Madison, WI*

9:20 D-59 Spatially Resolved Determination of Stress in Thin Films and Devices from Curvature Measurements
N. Herres, *Interstate University of Applied Sciences, Buchs, Switzerland*

9:40 D-57 NIST SRM 2000—A High Resolution X-ray Diffraction Standard Reference Material
D. Windover, D.L. Gil, A. Henins, J.P. Cline, *National Institute of Standards & Technology, Gaithersburg, MD*

10:00 Break

10:20 D-89 *Invited*— Six Ways of Determining Film Thickness from High Resolution XRD Data
A.J. Ying, I.C. Noyan, *Columbia University, New York, NY*
C.E. Murray, *IBM T. J. Watson Research Laboratory, Yorktown Heights, NY*

10:50 D-28 High-Resolution X-ray Scattering Methods for the Structural Characertization of Epitaxial Nitride Structures
J.F. Woitok, *PANalytical B.V., Almelo, Netherlands*

11:10 D-87 Grazing Incidence In-Plane X-ray Diffraction from Epitaxial Fe/MgO/Fe and Fe/Au/MgO/Fe Tunnel Junctions
D.S. Eastwood, M. Abes, B.K. Tanner, *University of Durham, Durham, United Kingdom*
T.P.A. Hase, *University of Warwick, Coventry, United Kingdom*
M. Ali, B.J. Hickey, *University of Leeds, Leeds, United Kingdom*

XRD: Rietveld Analysis
Friday a.m. Centennial

Chairs: **S.T. Misture,** *NYS College of Ceramics at Alfred University, Alfred, NY*
R.L. Snyder, *Georgia Institute of Technology, Atlanta, GA*

8:30 D-86 *Invited*— Structure Solution and Refinement Approaches for Oxide Ceramics
S.T. Misture, *Alfred University, Alfred, NY*

9:00 D-54 Charge-Flipping Structure Solution from Single Crystal and Powder Diffraction Data
A. Kern, A.A. Coelho, *Bruker AXS, Karlsruhe, Germany*

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